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February 2012

FDB2552 / FDP2552

N-Channel PowerTrench® MOSFET **150V**, **37A**, **36m**Ω

Features

- $r_{DS(ON)} = 32m\Omega$ (Typ.), $V_{GS} = 10V$, $I_D = 16A$
- $Q_{\alpha}(tot) = 39nC (Typ.), V_{GS} = 10V$
- · Low Miller Charge
- Low Q_{RR} Body Diode
- UIS Capability (Single Pulse and Repetitive Pulse)

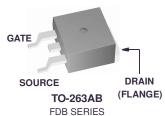
Formerly developmental type 82869

Applications

- DC/DC Converters and Off-line UPS
- · Distributed Power Architectures and VRMs
- · Primary Switch for 24V and 48V Systems
- · High Voltage Synchronous Rectifier









MOSFET Maximum Ratings T_C = 25°C unless otherwise noted

Symbol	Parameter	Ratings	Units
V _{DSS}	Drain to Source Voltage	150	V
V _{GS}	Gate to Source Voltage	±20	V
	Drain Current		
	Continuous ($T_C = 25^{\circ}C$, $V_{GS} = 10V$)	37	Α
I_D	Continuous (T _C = 100°C, V _{GS} = 10V)	26	Α
	Continuous ($T_{amb} = 25^{\circ}C$, $V_{GS} = 10V$) with $R_{\theta JA} = 43^{\circ}C/W$	5	Α
	Pulsed	Figure 4	Α
E _{AS}	Single Pulse Avalanche Energy (Note 1)	390	mJ
P _D	Power dissipation	150	W
	Derate above 25°C	1.0	W/°C
T _J , T _{STG}	Operating and Storage Temperature	-55 to 175	°C

Thermal Characteristics

$R_{\theta JC}$	Thermal Resistance Junction to Case TO-220, TO-263	1.0	°C/W
$R_{\theta JA}$	Thermal Resistance Junction to Ambient TO-220, TO-263 (Note 2)	62	°C/W
$R_{\theta JA}$	Thermal Resistance Junction to Ambient TO-263, 1in ² copper pad area	43	°C/W

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDB2552	FDB2552	TO-263AB	330mm	24mm	800 units
FDP2552	FDP2552	TO-220AB	Tube	N/A	50 units

Test Conditions

Min

Тур

Max

Units

Electrical Characteristics $T_C = 25^{\circ}C$ unless otherwise noted

Parameter

B _{VDSS}	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS}$	= 0V	150	-	-	V
	7 0	V _{DS} = 120V		-	-	1	
I _{DSS}	Zero Gate Voltage Drain Current	$V_{GS} = 0V$	$T_{\rm C} = 150^{\rm o}{\rm C}$	-	-	250	μΑ
I _{GSS}	Gate to Source Leakage Current	$V_{GS} = \pm 20V$		-	-	±100	nA
On Chai	racteristics						
V _{GS(TH)}	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D =$	250μΑ	2	-	4	V
5.5(1.1)		I _D = 16A, V _{GS} =		-	0.032	0.036	
_	Drain to Source On Resistance	$I_D = 8A, V_{GS} = 6$	V	-	0.036	0.054	0
r _{DS(ON)}	Drain to Source On Resistance	$I_D = 16A, V_{GS} = T_J = 175^{\circ}C$		-	0.084	0.097	Ω
Dynamic C _{ISS}	C Characteristics Input Capacitance	<u> </u>		_	2800	- 1	pF
C _{OSS}	Output Capacitance	$V_{DS} = 25V, V_{GS} = 0V,$ $f = 1MHz$		_	285	-	pF
C _{RSS}	Reverse Transfer Capacitance			_	55	-	pF
Q _{g(TOT)}	Total Gate Charge at 10V	V _{GS} = 0V to 10V			39	51	nC
	<u> </u>				5.2	6.8	
	Threshold Gate Charge	$V_{GS} = 0V \text{ to } 2V$	$V_{DD} = 75V$	-	5.2	0.0	nC
$Q_{g(TH)}$	Threshold Gate Charge Gate to Source Gate Charge	$V_{GS} = 0V \text{ to } 2V$	JV _{DD} = 75V I _D = 16A	-	13.5	-	
Q _{g(TH)} Q _{gs}		$V_{GS} = 0V \text{ to } 2V$			<u> </u>		nC
$Q_{g(TH)}$ Q_{gs} Q_{gs2}	Gate to Source Gate Charge	V _{GS} = 0V to 2V	$I_{D} = 16A$	-	13.5	-	nC nC
$\begin{array}{c} Q_{g(TH)} \\ Q_{gs} \\ Q_{gs2} \\ Q_{gd} \end{array}$	Gate to Source Gate Charge Gate Charge Threshold to Plateau Gate to Drain "Miller" Charge	V _{GS} = 0V to 2V	$I_{D} = 16A$	-	13.5 8.4	-	nC nC nC
$\begin{array}{c} Q_{g(TH)} \\ Q_{gs} \\ Q_{gs2} \\ Q_{gd} \end{array}$	Gate to Source Gate Charge Gate Charge Threshold to Plateau	V _{GS} = 0V to 2V	$I_{D} = 16A$	-	13.5 8.4	-	nC nC

t _{ON}	Turn-On Time		-	-	62	ns
t _{d(ON)}	Turn-On Delay Time		-	12	-	ns
t _r	Rise Time	V _{DD} = 75V, I _D = 16A	-	29	-	ns
t _{d(OFF)}	Turn-Off Delay Time	$V_{GS} = 10V, R_{GS} = 8.2\Omega$	-	36	-	ns
t _f	Fall Time		-	29	-	ns
t _{OFF}	Turn-Off Time		-	-	97	ns

Drain-Source Diode Characteristics

V _{SD}	Source to Drain Diode Voltage	I _{SD} = 16A	-	-	1.25	V
	Source to Drain blode voltage	I _{SD} = 8A	-	-	1.0	V
t _{rr}	Reverse Recovery Time	$I_{SD} = 16A$, $dI_{SD}/dt = 100A/\mu s$	-	-	90	ns
Q _{RR}	Reverse Recovered Charge	$I_{SD} = 16A$, $dI_{SD}/dt = 100A/\mu s$	-	-	242	nC

Notes: 1: Starting $T_J = 25^{\circ}C$, L = 7.8mH, $I_{AS} = 10A$. 2: Pulse Width = 100s

Symbol

175

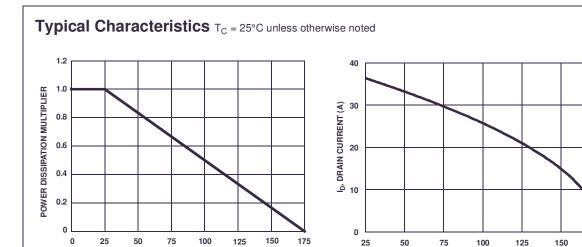


Figure 1. Normalized Power Dissipation vs Ambient Temperature

T_C, CASE TEMPERATURE (°C)

Figure 2. Maximum Continuous Drain Current vs Case Temperature

T_C, CASE TEMPERATURE (°C)

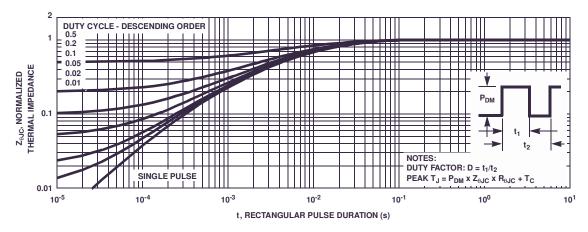


Figure 3. Normalized Maximum Transient Thermal Impedance

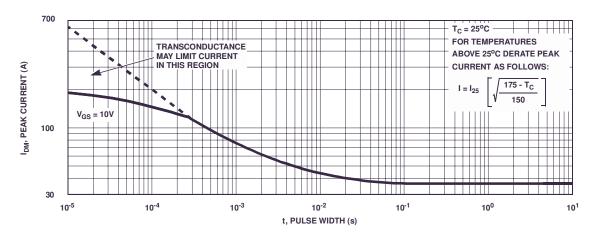
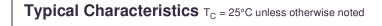
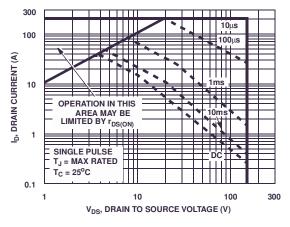


Figure 4. Peak Current Capability

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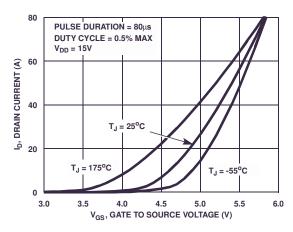
If R = 0 $t_{AV} = (L)(t_{AS})/(1.3^*\text{RATED BV}_{DSS} - V_{DD})$ If R \neq 0 $t_{AV} = (L/R)\ln[(t_{AS}*R)/(1.3^*\text{RATED BV}_{DSS} - V_{DD}) + 1]$ $STARTING T_J = 25^\circ\text{C}$ 1 0.01 0.1 1 1 10 $t_{AV}, \text{TIME IN AVALANCHE (ms)}$

Figure 5. Forward Bias Safe Operating Area

NOTE: Refer to Fairchild Application Notes AN7514 and AN7515

Figure 6. Unclamped Inductive Switching

Capability



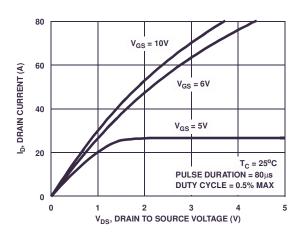
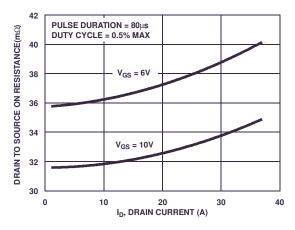


Figure 7. Transfer Characteristics

Figure 8. Saturation Characteristics



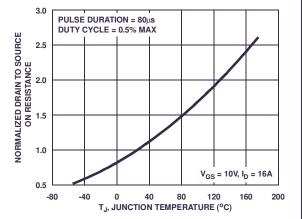


Figure 9. Drain to Source On Resistance vs Drain Current

Figure 10. Normalized Drain to Source On Resistance vs Junction Temperature

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Typical Characteristics $T_C = 25^{\circ}C$ unless otherwise noted

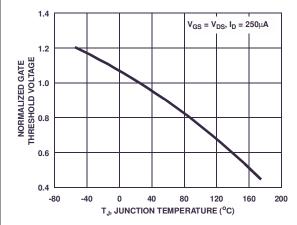
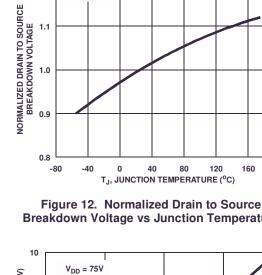


Figure 11. Normalized Gate Threshold Voltage vs **Junction Temperature**



1.2

I_D = 250μA

Breakdown Voltage vs Junction Temperature

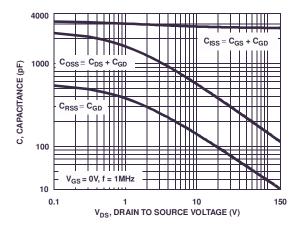


Figure 13. Capacitance vs Drain to Source Voltage

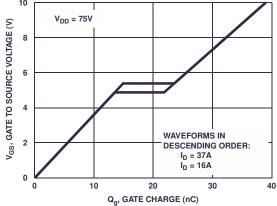


Figure 14. Gate Charge Waveforms for Constant **Gate Currents**

Test Circuits and Waveforms

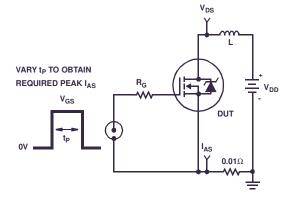


Figure 15. Unclamped Energy Test Circuit

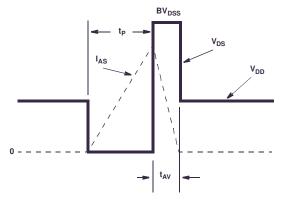


Figure 16. Unclamped Energy Waveforms

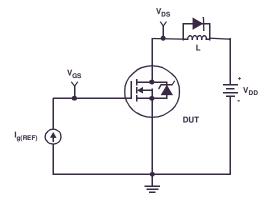


Figure 17. Gate Charge Test Circuit

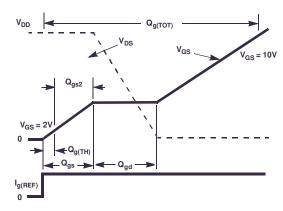


Figure 18. Gate Charge Waveforms

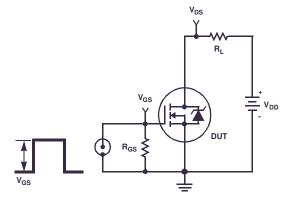


Figure 19. Switching Time Test Circuit

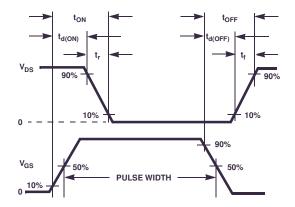


Figure 20. Switching Time Waveforms

Thermal Resistance vs. Mounting Pad Area

The maximum rated junction temperature, T_{JM} , and the thermal resistance of the heat dissipating path determines the maximum allowable device power dissipation, P_{DM} , in an application. Therefore the application's ambient temperature, T_A (°C), and thermal resistance $R_{\theta JA}$ (°C/W) must be reviewed to ensure that T_{JM} is never exceeded. Equation 1 mathematically represents the relationship and serves as the basis for establishing the rating of the part.

$$P_{DM} = \frac{(T_{JM} - T_A)}{R_{\theta JA}} \tag{EQ. 1}$$

In using surface mount devices such as the TO-263 package, the environment in which it is applied will have a significant influence on the part's current and maximum power dissipation ratings. Precise determination of P_{DM} is complex and influenced by many factors:

- Mounting pad area onto which the device is attached and whether there is copper on one side or both sides of the board.
- The number of copper layers and the thickness of the board.
- 3. The use of external heat sinks.
- 4. The use of thermal vias.
- 5. Air flow and board orientation.
- For non steady state applications, the pulse width, the duty cycle and the transient thermal response of the part, the board and the environment they are in.

Fairchild provides thermal information to assist the designer's preliminary application evaluation. Figure 21 defines the $R_{\theta JA}$ for the device as a function of the top copper (component side) area. This is for a horizontally positioned FR-4 board with 1oz copper after 1000 seconds of steady state power with no air flow. This graph provides the necessary information for calculation of the steady state junction temperature or power dissipation. Pulse applications can be evaluated using the Fairchild device Spice thermal model or manually utilizing the normalized maximum transient thermal impedance curve.

Thermal resistances corresponding to other copper areas can be obtained from Figure 21 or by calculation using Equation 2 or 3. Equation 2 is used for copper area defined in inches square and equation 3 is for area in centimeters square. The area, in square inches or square centimeters is the top copper area including the gate and source pads.

$$R_{\theta JA} = 26.51 + \frac{19.84}{(0.262 + Area)}$$
 (EQ. 2)

Area in Inches Squared

$$R_{\Theta JA} = 26.51 + \frac{128}{(1.69 + Area)}$$
 (EQ. 3)

Area in Centimeters Squared

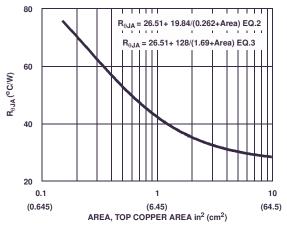
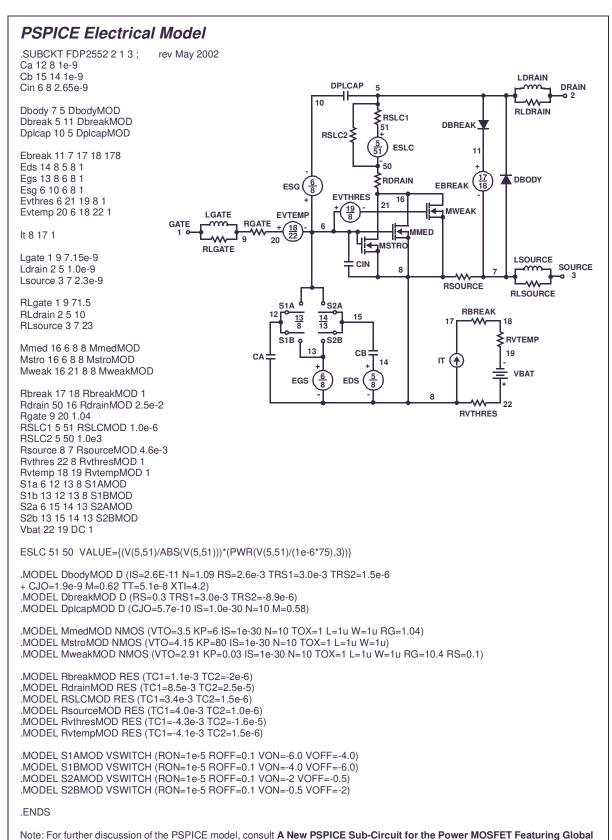


Figure 21. Thermal Resistance vs Mounting
Pad Area



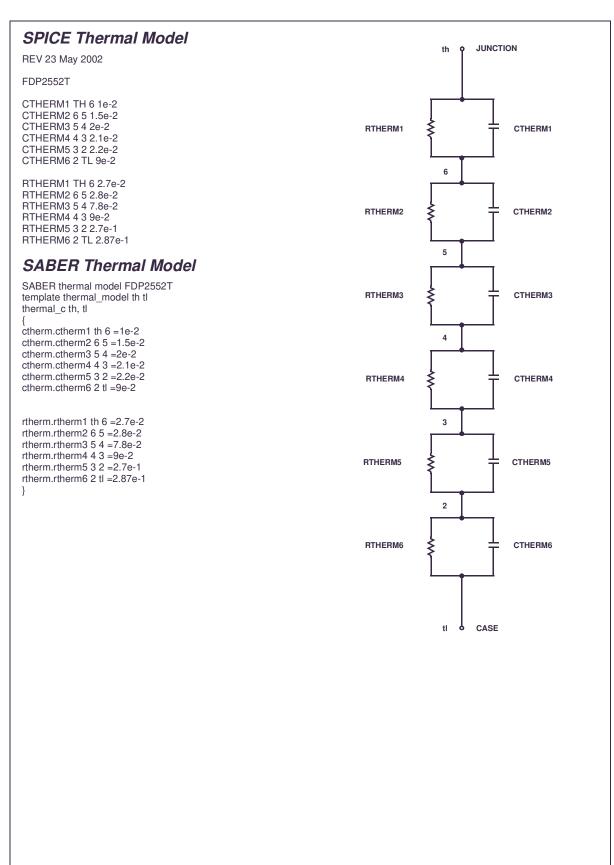
Temperature Options; IEEE Power Electronics Specialist Conference Records, 1991, written by William J. Hepp and C. Frank

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Wheatley.

SABER Electrical Model REV May 2002 template FDP2552 n2,n1,n3 electrical n2,n1,n3 var i iscl dp..model dbodymod = (isl=2.6e-11,nl=1.09,rs=2.6e-3,trs1=3.0e-3,trs2=1.5e-6,cjo=1.9e-9,m=0.62,tt=5.1e-8,xti=4.2) dp., model dbreakmod = (rs=0.3, trs1=3,0e-3, trs2=-8,9e-6) dp..model dplcapmod = (cjo=5.7e-10,isl=10.0e-30,nl=10,m=0.58) $m..model mmedmod = (type=_n,vto=3.5,kp=6,is=1e-30,tox=1)$ m..model mstrongmod = (type=_n,vto=4.15,kp=80,is=1e-30, tox=1) m..model mweakmod = $(type=_n, vto=2.91, kp=0.03, is=1e-30, tox=1, rs=0.1)$ I DRAIN sw_vcsp..model s1amod = (ron=1e-5,roff=0.1,von=-6.0,voff=-4.0) DPI CAP DRAIN sw_vcsp..model s1bmod = (ron=1e-5,roff=0.1,von=-4.0,voff=-6.0) 10 sw_vcsp..model s2amod = (ron=1e-5,roff=0.1,von=-2,voff=-0.5) RLDRAIN sw_vcsp..model s2bmod = (ron=1e-5,roff=0.1,von=-0.5,voff=-2) ₹RSLC1 c.ca n12 n8 = 1e-951 c.cb n15 n14 = 1e-9RSLC2 ₹ ISCL c.cin n6 n8 = 2.65e-9DBREAK 3 50 dp.dbody n7 n5 = model=dbodymod **≷**RDRAIN dp.dbreak n5 n11 = model=dbreakmod $ESG(\frac{6}{8})$ dp.dplcap n10 n5 = model=dplcapmod DBODY **EVTHRES** 21 MWFAK **LGATE EVTEMP** spe.ebreak n11 n7 n17 n18 = 178 **GATE RGATE** 182 spe.eds n14 n8 n5 n8 = 1 FRREAK MMED ₩-20 spe.egs n13 n8 n6 n8 = 1 **■**MSTR RLGATE spe.esg n6 n10 n6 n8 = 1 CIN spe.evthres n6 n21 n19 n8 = 1 SOURCE spe.evtemp n20 n6 n18 n22 = 1 RSOURCE RLSOURCE i.it n8 n17 = 1RBREAK 14 13 18 I.lgate n1 n9 = 7.15e-9I.ldrain n2 n5 = 1.0e-9o S2B **₹**RVTEMP S₁B I.lsource n3 n7 = 2.3e-9СВ 19 CA IT 14 res.rlgate n1 n9 = 71.5 VRAT <u>5</u> res.rldrain n2 n5 = 10**FGS FDS** res.rlsource n3 n7 = 23 **RVTHRES** m.mmed n16 n6 n8 n8 = model=mmedmod, l=1u, w=1u m.mstrong n16 n6 n8 n8 = model=mstrongmod, l=1u, w=1u m.mweak n16 n21 n8 n8 = model=mweakmod, l=1u, w=1u res.rbreak n17 n18 = 1, tc1=1.1e-3,tc2=-2e-6res.rdrain n50 n16 = 2.5e-2, tc1=8.5e-3,tc2=2.5e-5 res.rgate n9 n20 = 1.04res.rslc1 n5 n51 = 1.0e-6, tc1=3.4e-3,tc2=1.5e-6 res.rslc2 n5 n50 = 1.0e3res.rsource n8 n7 = 4.6e-3, tc1=4.0e-3,tc2=1.0e-6 res.rvthres n22 n8 = 1, tc1=-4.3e-3, tc2=-1.6e-5res.rvtemp n18 n19 = 1, tc1=-4.1e-3,tc2=1.5e-6 sw vcsp.s1a n6 n12 n13 n8 = model=s1amod sw_vcsp.s1b n13 n12 n13 n8 = model=s1bmod sw_vcsp.s2a n6 n15 n14 n13 = model=s2amod sw_vcsp.s2b n13 n15 n14 n13 = model=s2bmod v.vbat n22 n19 = dc=1 equations { i (n51->n50) +=iscl (v(n51,n50) = ((v(n5,n51)/(1e-9+abs(v(n5,n51))))*((abs(v(n5,n51)*1e6/75))**3))

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